

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV351235065US

Applicant : Akio Ishikawa
Application No. : N/A
Filed : September 29, 2003
Title : IMAGE DEFECT INSPECTION METHOD, IMAGE DEFECT
INSPECTION APPARATUS AND APPEARANCE INSPECTION
APPARATUS
Grp./Div. : N/A
Examiner : N/A
Docket No. : 51272/DBP/A400

**INFORMATION DISCLOSURE STATEMENT
37 CFR § 1.97(b)**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PostOffice Box 7068
Pasadena, CA 91109-7068
September 29, 2003


Commissioner:

In compliance with the duty of disclosure under 37 CFR §§ 1.56, 1.97 and 1.98, and in accordance with the provisions in the Manual of Patent Examining Procedure §§ 609 and 707.05(b), enclosed is FORM PTO/SB/08A/B listing the references that are known to applicant. Copies of each of the listed references are enclosed. References listed as "ON ORDER" will be provided upon receipt of the same. This filing is timely because it is made during one of the periods described in 37 CFR § 1.97(b).

It is respectfully requested that the listed references be considered in the examination of this application and identified on the list of references cited on the patent issuing for this application. Applicant also requests that an initialed copy of FORM PTO/SB/08A/B be entered in the application file and returned to applicant with the next communication from the Office in accordance with MPEP § 609.

Respectfully submitted,

CHRISTIE, PARKER & HALE, LLP

By 
D. Bruce Prout
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DBP/aam

Enclosures: Form PTO/SB/08A/B, w/references
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FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	Attorney Docket Number	51272/DBP/A400
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)	Application Number	N/A
	Filing Date	September 29, 2003
	Applicant(s)	Akio Ishikawa
	Group Art Unit	N/A
	Examiner Name	N/A

U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	Cite No. ¹	<u>DOCUMENT NUMBER</u> Number - Kind Code ² (If Known)	Publication Date MM-DD-YYYY	Name of Patentee

FOREIGN PATENT DOCUMENTS					
EXAMINER INITIALS	Cite No. ¹	<u>FOREIGN PATENT DOCUMENT</u> Country Code ³ - Number ⁴ - Kind Code ⁵ (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T ⁶ (✓)
		JP 4-107946 (ON ORDER)	04-09-1992	Taniguchi et al.	Patent Abstract of Japan
		JP 5-047886 (ON ORDER)	02-26-1993	Jingu	Patent Abstract of Japan
		JP 2002-022421 (ON ORDER)	01-23-2002	Hikita et al.	Patent Abstract of Japan

OTHER DOCUMENTS		
EXAMINER INITIALS	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Patent Abstract of Japan, Publication Number 04-107946, Published on 04-09-1992, in the name of Taniguchi et al.
		Patent Abstract of Japan, Publication Number 05-047886, Published on 02-26-1993, in the name of Jingu
		Patent Abstract of Japan, Publication Number 2002-022421, Published on 01-23-2002, in the name of Hikita et al.

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EXAMINER SIGNATURE	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.pto.gov or MPEP 901.4. ³ Enter Office that issued the document, by the two-letter code (WIPO standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English Language Translation is attached.	